## Applicant(s)/Patent Under Application/Control No. Reexamination 10/708,827 BEENAU ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Daniel I. Walsh 2876 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY \* US-2005/0232471 10-2005 Baer, Richard 382/115 Α \* US-5,988,497 Wallace, Michelle H. 11-1999 235/382.5 В US-С US-D US-Ε US-F US-G US-Н US-1 US-J US-Κ US-L US-М **FOREIGN PATENT DOCUMENTS Document Number** Date Country Classification Name Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R S т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

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